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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	100MHz
Connectivity	CANbus, EBI/EMI, I ² C, IrDA, SD, SPI, UART/USART
Peripherals	DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	90
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 42x16b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	121-LFBGA
Supplier Device Package	121-MAPBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mk10dn512vmc10r

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

3.4 Definition: Rating

A *rating* is a minimum or maximum value of a technical characteristic that, if exceeded, may cause permanent chip failure:

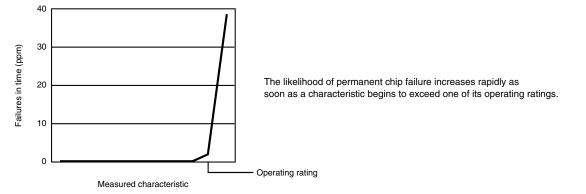
- Operating ratings apply during operation of the chip.
- Handling ratings apply when the chip is not powered.

3.4.1 Example

This is an example of an operating rating:

Symbol	Description	Min.	Max.	Unit
V _{DD}	1.0 V core supply voltage	-0.3	1.2	V

3.5 Result of exceeding a rating



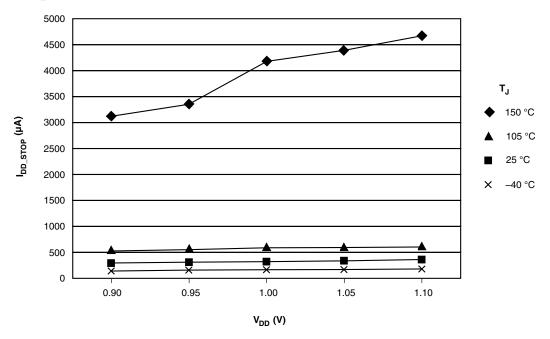
3.8.1 Example 1

This is an example of an operating behavior that includes a typical value:

Symbol	Description	Min.	Тур.	Max.	Unit
I _{WP}	Digital I/O weak pullup/pulldown current	10	70	130	μΑ

3.8.2 Example 2

This is an example of a chart that shows typical values for various voltage and temperature conditions:



3.9 Typical value conditions

Typical values assume you meet the following conditions (or other conditions as specified):

Symbol	Description	Value	Unit
T _A	Ambient temperature	25	C°
V _{DD}	3.3 V supply voltage	3.3	V

4 Ratings

4.1 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T _{STG}	Storage temperature	-55	150	°C	1
T _{SDR}	Solder temperature, lead-free	_	260	°C	2

1. Determined according to JEDEC Standard JESD22-A103, High Temperature Storage Life.

2. Determined according to IPC/JEDEC Standard J-STD-020, Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices.

4.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	_	3		1

1. Determined according to IPC/JEDEC Standard J-STD-020, Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices.

4.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V _{HBM}	Electrostatic discharge voltage, human body model	-2000	+2000	V	1
V _{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	2
I _{LAT}	Latch-up current at ambient temperature of 105°C	-100	+100	mA	

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.

2. Determined according to JEDEC Standard JESD22-C101, Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components.

4.4 Voltage and current operating ratings

Symbol	Description	Min.	Max.	Unit
V _{DD}	Digital supply voltage	-0.3	3.8	V

Table continues on the next page ...

5.2.3 Voltage and current operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
V _{OH}	Output high voltage — high drive strength				
	• 2.7 V \leq V _{DD} \leq 3.6 V, I _{OH} = -9mA	V _{DD} – 0.5	_	V	
	• 1.71 V \leq V _{DD} \leq 2.7 V, I _{OH} = -3mA	V _{DD} – 0.5	—	V	
	Output high voltage — low drive strength				
	• 2.7 V \leq V _{DD} \leq 3.6 V, I _{OH} = -2mA	V _{DD} – 0.5	_	V	
	• $1.71 \text{ V} \le \text{V}_{\text{DD}} \le 2.7 \text{ V}, \text{ I}_{\text{OH}} = -0.6 \text{mA}$	V _{DD} – 0.5	_	V	
I _{OHT}	Output high current total for all ports		100	mA	
V _{OL}	Output low voltage — high drive strength				
	• 2.7 V \leq V _{DD} \leq 3.6 V, I _{OL} = 9mA		0.5	V	
	• 1.71 V \leq V _{DD} \leq 2.7 V, I _{OL} = 3mA	_	0.5	V	
	Output low voltage — low drive strength			v v	
	• 2.7 V \leq V _{DD} \leq 3.6 V, I _{OL} = 2mA		0.5	V	
	• $1.71 \text{ V} \le \text{V}_{\text{DD}} \le 2.7 \text{ V}, \text{ I}_{\text{OL}} = 0.6 \text{mA}$	_	0.5	V	
I _{OLT}	Output low current total for all ports	_	100	mA	
I _{IN}	Input leakage current (per pin) for full temperature range	—	1	μA	1
I _{IN}	Input leakage current (per pin) at 25°C		0.025	μA	1
I _{OZ}	Hi-Z (off-state) leakage current (per pin)	—	1	μA	
R _{PU}	Internal pullup resistors	20	50	kΩ	2
R _{PD}	Internal pulldown resistors	20	50	kΩ	3

 Table 4. Voltage and current operating behaviors

1. Measured at VDD=3.6V

2. Measured at V_{DD} supply voltage = V_{DD} min and Vinput = V_{SS}

3. Measured at V_{DD} supply voltage = V_{DD} min and Vinput = V_{DD}

5.2.4 Power mode transition operating behaviors

All specifications except t_{POR} , and VLLSx \rightarrow RUN recovery times in the following table assume this clock configuration:

- CPU and system clocks = 100 MHz
- Bus clock = 50 MHz
- FlexBus clock = 50 MHz
- Flash clock = 25 MHz

General

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
I _{DD_VBAT}	Average current when CPU is not accessing RTC registers					10
	• @ 1.8V					
	• @ -40 to 25°C	_	0.57	0.67	μA	
	• @ 70°C	_	0.90	1.2	μA	
	• @ 105°C		2.4	3.5	μΑ	
	• @ 3.0V					
	 @ -40 to 25°C 	_	0.67	0.94	μA	
	• @ 70°C		1.0	1.4	μΑ	
	• @ 105°C	_	2.7	3.9	μA	

Table 6. Power consumption operating behaviors (continued)

- 1. The analog supply current is the sum of the active or disabled current for each of the analog modules on the device. See each module's specification for its supply current.
- 100MHz core and system clock, 50MHz bus and FlexBus clock, and 25MHz flash clock . MCG configured for FEI mode. All peripheral clocks disabled.
- 3. 100MHz core and system clock, 50MHz bus and FlexBus clock, and 25MHz flash clock. MCG configured for FEI mode. All peripheral clocks enabled.
- 4. Max values are measured with CPU executing DSP instructions.
- 5. 25MHz core and system clock, 25MHz bus clock, and 12.5MHz FlexBus and flash clock. MCG configured for FEI mode.
- 4 MHz core, system, FlexBus, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks disabled. Code executing from flash.
- 7. 4 MHz core, system, FlexBus, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks enabled but peripherals are not in active operation. Code executing from flash.
- 8. 4 MHz core, system, FlexBus, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks disabled.
- 9. Data reflects devices with 128 KB of RAM.
- 10. Includes 32kHz oscillator current and RTC operation.

5.2.5.1 Diagram: Typical IDD_RUN operating behavior

The following data was measured under these conditions:

- MCG in FBE mode for 50 MHz and lower frequencies. MCG in FEE mode at greater than 50 MHz frequencies.
- No GPIOs toggled
- Code execution from flash with cache enabled
- For the ALLOFF curve, all peripheral clocks are disabled except FTFL

General

3. Specified according to Annex D of IEC Standard 61967-2, Measurement of Radiated Emissions – TEM Cell and Wideband TEM Cell Method

5.2.7 Designing with radiated emissions in mind

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions:

- 1. Go to www.freescale.com.
- 2. Perform a keyword search for "EMC design."

5.2.8 Capacitance attributes

Table 8. Capacitance attributes

Symbol	Description	Min.	Max.	Unit
C _{IN_A}	Input capacitance: analog pins	—	7	pF
C _{IN_D}	Input capacitance: digital pins	—	7	pF

5.3 Switching specifications

5.3.1 Device clock specifications

Table 9. Device clock specifications

Symbol	Description	Min.	Max.	Unit	Notes
	Normal run mode	Э		•	
f _{SYS}	System and core clock	_	100	MHz	
f _{BUS}	Bus clock	_	50	MHz	
FB_CLK	FlexBus clock	_	50	MHz	
f _{FLASH}	Flash clock	—	25	MHz	
f _{LPTMR}	LPTMR clock	_	25	MHz	
	VLPR mode ¹				
f _{SYS}	System and core clock	_	4	MHz	
f _{BUS}	Bus clock	—	4	MHz	
FB_CLK	FlexBus clock	_	4	MHz	
f _{FLASH}	Flash clock	—	0.5	MHz	
f _{ERCLK}	External reference clock	—	16	MHz	
f _{LPTMR_pin}	LPTMR clock	—	25	MHz	
f _{LPTMR_ERCLK}	LPTMR external reference clock	—	16	MHz	

Table continues on the next page...

Symbol	Description		Max.	Unit	Notes
f _{FlexCAN_ERCLK} FlexCAN external reference clock		—	8	MHz	
f _{I2S_MCLK}	f _{I2S_MCLK} I2S master clock		12.5	MHz	
f _{I2S_BCLK}	I2S bit clock		4	MHz	

Table 9. Device clock specifications (continued)

1. The frequency limitations in VLPR mode here override any frequency specification listed in the timing specification for any other module.

5.3.2 General switching specifications

These general purpose specifications apply to all signals configured for GPIO, UART, CAN, CMT, and I²C signals.

Table 10. General switching specifications

Symbol	Description	Min.	Max.	Unit	Notes
	GPIO pin interrupt pulse width (digital glitch filter disabled) — Synchronous path	1.5	_	Bus clock cycles	1, 2
	GPIO pin interrupt pulse width (digital glitch filter disabled, analog filter enabled) — Asynchronous path	100	-	ns	3
	GPIO pin interrupt pulse width (digital glitch filter disabled, analog filter disabled) — Asynchronous path	16	—	ns	3
	External reset pulse width (digital glitch filter disabled)	100	_	ns	3
	Mode select (EZP_CS) hold time after reset deassertion	2	-	Bus clock cycles	
	Port rise and fall time (high drive strength)				4
	Slew disabled				
	• 1.71 ≤ V _{DD} ≤ 2.7V	_	12	ns	
	• $2.7 \le V_{DD} \le 3.6V$	_	6	ns	
	Slew enabled				
	• 1.71 ≤ V _{DD} ≤ 2.7V	_	36	ns	
	• $2.7 \le V_{DD} \le 3.6V$	_	24	ns	
	Port rise and fall time (low drive strength)				5
	Slew disabled				
	• 1.71 ≤ V _{DD} ≤ 2.7V	_	12	ns	
	• $2.7 \le V_{DD} \le 3.6V$	_	6	ns	
	Slew enabled				
	• 1.71 ≤ V _{DD} ≤ 2.7V	_	36	ns	
	• $2.7 \le V_{DD} \le 3.6V$	_	24	ns	

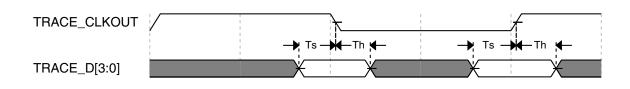


Figure 4. Trace data specifications

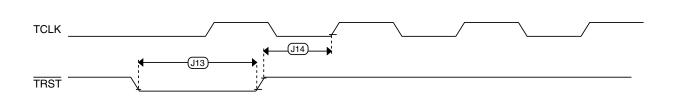
6.1.2 JTAG electricals

Symbol	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
J1	TCLK frequency of operation			MHz
	Boundary Scan	0	10	
	JTAG and CJTAG	0	25	
	Serial Wire Debug	0	50	
J2	TCLK cycle period	1/J1	_	ns
J3	TCLK clock pulse width			
	Boundary Scan	50	—	ns
	JTAG and CJTAG	20	_	ns
	Serial Wire Debug	10	—	ns
J4	TCLK rise and fall times		3	ns
J5	Boundary scan input data setup time to TCLK rise	20	—	ns
J6	Boundary scan input data hold time after TCLK rise	0	_	ns
J7	TCLK low to boundary scan output data valid	—	25	ns
J8	TCLK low to boundary scan output high-Z	_	25	ns
J9	TMS, TDI input data setup time to TCLK rise	8	—	ns
J10	TMS, TDI input data hold time after TCLK rise	1	—	ns
J11	TCLK low to TDO data valid	_	17	ns
J12	TCLK low to TDO high-Z	—	17	ns
J13	TRST assert time	100		ns
J14	TRST setup time (negation) to TCLK high	8		ns

Table 14. JTAG full voltage range electricals

Symbo	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V

Table continues on the next page ...





Peripheral operating requirements and behaviors

6.2 System modules

There are no specifications necessary for the device's system modules.

6.3 Clock modules

6.3.1 MCG specifications

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
f _{ints_ft}	Internal reference frequency (slow clock) — factory trimmed at nominal VDD and 25 °C	_	32.768	—	kHz	
f _{ints_t}	Internal reference frequency (slow clock) — user trimmed		_	39.0625	kHz	
$\Delta_{fdco_res_t}$	P_res_t Resolution of trimmed average DCO output frequency at fixed voltage and temperature — using SCTRIM and SCFTRIM		± 0.3	± 0.6	%f _{dco}	1
Δf _{dco_res_t} Resolution of trimmed average DCO output frequency at fixed voltage and temperature — using SCTRIM only		_	± 0.2	± 0.5	%f _{dco}	1
Δf_{dco_t}	Total deviation of trimmed average DCO output frequency over voltage and temperature		+0.5/-0.7	± 3	%f _{dco}	1
Δf_{dco_t}			± 0.3	± 3	%f _{dco}	1
f _{intf_ft}	Internal reference frequency (fast clock) — factory trimmed at nominal VDD and 25°C	_	4	—	MHz	
f _{intf_t}	Internal reference frequency (fast clock) — user trimmed at nominal VDD and 25 °C	3	_	5	MHz	
f _{loc_low}	Loss of external clock minimum frequency — RANGE = 00	(3/5) x f _{ints_t}	—	—	kHz	
f_{loc_high}	Loss of external clock minimum frequency — RANGE = 01, 10, or 11	(16/5) x f _{ints_t}	—	—	kHz	

Table 15. MCG specifications

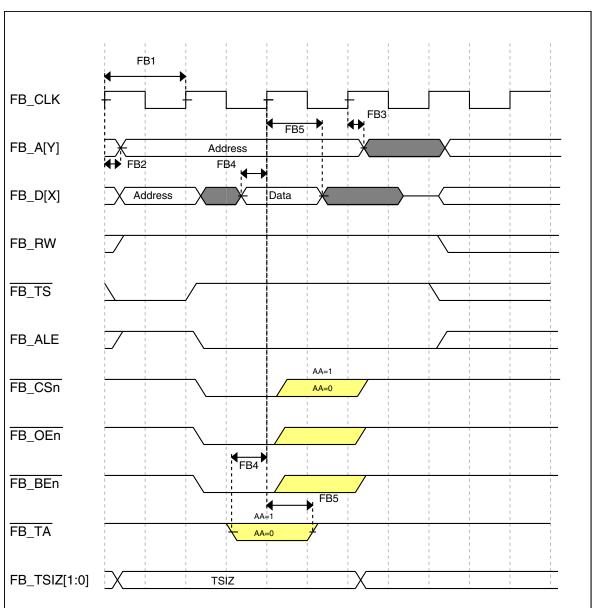
Table continues on the next page ...

	Table 16. Oscillator DC electrical specifications (continued)								
ol	Description	Min.	Тур.	Max.	Unit	Note			
с	Supply current — high gain mode (HGO=1)					1			

Table 16.	Oscillator DC electrical	specifications	(continued)
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Symbol	Description	Min.	Тур.	Max.	Unit	Notes
I _{DDOSC}	Supply current — high gain mode (HGO=1)					1
	• 32 kHz	_	25	_	μΑ	
	• 4 MHz	—	400	_	μΑ	
	• 8 MHz (RANGE=01)	_	500	_	μΑ	
	• 16 MHz	_	2.5	_	mA	
	• 24 MHz	_	3	_	mA	
	• 32 MHz	—	4	—	mA	
C _x	EXTAL load capacitance					2, 3
Cy	XTAL load capacitance	_				2, 3
R _F	Feedback resistor — low-frequency, low-power mode (HGO=0)	_	_	_	MΩ	2, 4
	Feedback resistor — low-frequency, high-gain mode (HGO=1)	_	10	_	MΩ	
	Feedback resistor — high-frequency, low-power mode (HGO=0)	—	_	_	MΩ	
	Feedback resistor — high-frequency, high-gain mode (HGO=1)	_	1	_	MΩ	
R _S	Series resistor — low-frequency, low-power mode (HGO=0)	_	—	_	kΩ	
	Series resistor — low-frequency, high-gain mode (HGO=1)		200		kΩ	
	Series resistor — high-frequency, low-power mode (HGO=0)				kΩ	
	Series resistor — high-frequency, high-gain mode (HGO=1)					
		_	0	_	kΩ	
V _{pp} ⁵	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, low-power mode (HGO=0)	_	0.6	_	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, high-gain mode (HGO=1)	_	V _{DD}	_	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, low-power mode (HGO=0)	_	0.6	_	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, high-gain mode (HGO=1)	_	V _{DD}	_	V	

- 1. V_{DD} =3.3 V, Temperature =25 °C
- 2. See crystal or resonator manufacturer's recommendation
- 3. C_x, C_y can be provided by using either the integrated capacitors or by using external components.
- 4. When low power mode is selected, R_F is integrated and must not be attached externally.
- 5. The EXTAL and XTAL pins should only be connected to required oscillator components and must not be connected to any other devices.



Peripheral operating requirements and behaviors

Figure 10. FlexBus read timing diagram

Symbol	Description	Conditions	Min.	Typ. ¹	Max.	Unit	Notes
C _{rate}	ADC conversion	16-bit mode					5
	rate	No ADC hardware averaging	37.037	—	461.467	Ksps	
		Continuous conversions enabled, subsequent conversion time					

 Table 27.
 16-bit ADC operating conditions (continued)

- Typical values assume V_{DDA} = 3.0 V, Temp = 25 °C, f_{ADCK} = 1.0 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
- 2. DC potential difference.
- 3. This resistance is external to MCU. The analog source resistance must be kept as low as possible to achieve the best results. The results in this data sheet were derived from a system which has < 8 Ω analog source resistance. The R_{AS}/C_{AS} time constant should be kept to < 1ns.
- 4. To use the maximum ADC conversion clock frequency, the ADHSC bit must be set and the ADLPC bit must be clear.
- 5. For guidelines and examples of conversion rate calculation, download the ADC calculator tool

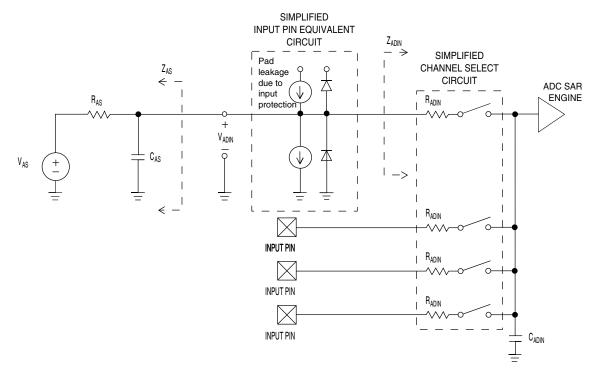


Figure 12. ADC input impedance equivalency diagram

6.6.1.2 16-bit ADC electrical characteristics Table 28. 16-bit ADC characteristics (V_{REFH} = V_{DDA}, V_{REFL} = V_{SSA})

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
I _{DDA_ADC}	Supply current		0.215		1.7	mA	3

Table continues on the next page ...

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
	ADC	• ADLPC = 1, ADHSC = 0	1.2	2.4	3.9	MHz	$t_{ADACK} = 1/$
	asynchronous clock source	• ADLPC = 1, ADHSC = 1	2.4	4.0	6.1	MHz	f _{ADACK}
f _{ADACK}		• ADLPC = 0, ADHSC = 0	3.0	5.2	7.3	MHz	
		• ADLPC = 0, ADHSC = 1	4.4	6.2	9.5	MHz	
	Sample Time	See Reference Manual chapter	for sample t	imes	1 1		
TUE	Total unadjusted	12-bit modes		±4	±6.8	LSB ⁴	5
	error	 <12-bit modes 	—	±1.4	±2.1		
DNL	Differential non-	12-bit modes	—	±0.7	-1.1 to +1.9	LSB ⁴	5
	linearity				-0.3 to 0.5		
		 <12-bit modes 	—	±0.2			
INL	Integral non-	12-bit modes		±1.0	-2.7 to +1.9	LSB ⁴	5
	linearity				-0.7 to +0.5		
		 <12-bit modes 	_	±0.5			
E _{FS}	Full-scale error	12-bit modes	_	-4	-5.4	LSB ⁴	V _{ADIN} =
		<12-bit modes	—	-1.4	-1.8		V _{DDA}
Eq	Quantization	16-bit modes	_	-1 to 0	_	LSB ⁴	5
	error	• ≤13-bit modes	—	_	±0.5		
ENOB	Effective number	16-bit differential mode					6
	of bits	• Avg = 32	12.8	14.5	_	bits	
		• Avg = 4	11.9	13.8	_	bits	
		16-bit single-ended mode					
		• Avg = 32	12.2	13.9		bits	
		• Avg = 4	11.4	13.1		bits	
	Signal-to-noise	See ENOB					
SINAD	plus distortion		6.02	2 × ENOB +	1.76	dB	
THD	Total harmonic	16-bit differential mode					7
	distortion	• Avg = 32	—	-94		dB	
		16-bit single-ended mode		05			
		• Avg = 32	_	-85		dB	
SFDR	Spurious free	16-bit differential mode					7
	dynamic range	• Avg = 32	82	95	-	dB	
		16-bit single-ended mode	78	90		dB	
		• Avg = 32	10	90		uВ	

Table 28.	16-bit ADC characteristics	$(V_{REFH} = V_{DDA})$	$V_{REFL} = V_{SS}$	A) (continued)
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Peripheral operating requirements and behaviors

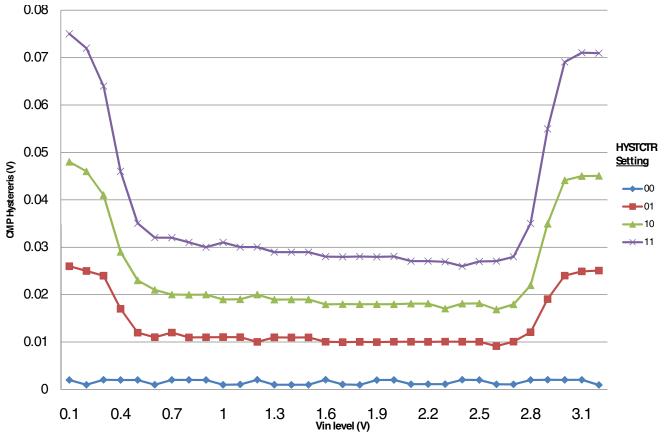


Figure 15. Typical hysteresis vs. Vin level (VDD=3.3V, PMODE=0)

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
V _{out}	Voltage reference output with factory trim at nominal V_{DDA} and temperature=25C	1.1915	1.195	1.1977	V	
V _{out}	Voltage reference output — factory trim	1.1584	—	1.2376	V	
V _{out}	Voltage reference output — user trim	1.193	—	1.197	V	
V _{step}	Voltage reference trim step	—	0.5	—	mV	
V _{tdrift}	Temperature drift (Vmax -Vmin across the full temperature range)	_	_	80	mV	
I _{bg}	Bandgap only current	—	—	80	μA	1
I _{lp}	Low-power buffer current	—	—	360	uA	1
I _{hp}	High-power buffer current	—	—	1	mA	1
ΔV_{LOAD}	Load regulation				μV	1, 2
	• current = ± 1.0 mA	_	200	_		
T _{stup}	Buffer startup time	-	_	100	μs	
V _{vdrift}	Voltage drift (Vmax -Vmin across the full voltage range)	—	2	—	mV	1

Table 35. VREF full-range operating behaviors

1. See the chip's Reference Manual for the appropriate settings of the VREF Status and Control register.

2. Load regulation voltage is the difference between the VREF_OUT voltage with no load vs. voltage with defined load

Table 36. VREF limited-range operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
T _A	Temperature	0	50	°C	

Table 37. VREF limited-range operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
V _{out}	Voltage reference output with factory trim	1.173	1.225	V	

6.7 Timers

See General switching specifications.

6.8 Communication interfaces

Peripheral operating requirements and behaviors

6.8.1 CAN switching specifications

See General switching specifications.

6.8.2 DSPI switching specifications (limited voltage range)

The DMA Serial Peripheral Interface (DSPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The tables below provide DSPI timing characteristics for classic SPI timing modes. Refer to the DSPI chapter of the Reference Manual for information on the modified transfer formats used for communicating with slower peripheral devices.

Num	Description	Min.	Max.	Unit	Notes
	Operating voltage	2.7	3.6	V	
	Frequency of operation	—	25	MHz	
DS1	DSPI_SCK output cycle time	2 x t _{BUS}	—	ns	
DS2	DSPI_SCK output high/low time	(t _{SCK} /2) – 2	(t _{SCK} /2) + 2	ns	
DS3	DSPI_PCSn valid to DSPI_SCK delay	(t _{BUS} x 2) – 2	—	ns	1
DS4	DSPI_SCK to DSPI_PCSn invalid delay	(t _{BUS} x 2) – 2	_	ns	2
DS5	DSPI_SCK to DSPI_SOUT valid	_	8	ns	
DS6	DSPI_SCK to DSPI_SOUT invalid	0	—	ns	
DS7	DSPI_SIN to DSPI_SCK input setup	14	—	ns	
DS8	DSPI_SCK to DSPI_SIN input hold	0		ns	

 Table 38.
 Master mode DSPI timing (limited voltage range)

1. The delay is programmable in SPIx_CTARn[PSSCK] and SPIx_CTARn[CSSCK].

2. The delay is programmable in SPIx_CTARn[PASC] and SPIx_CTARn[ASC].

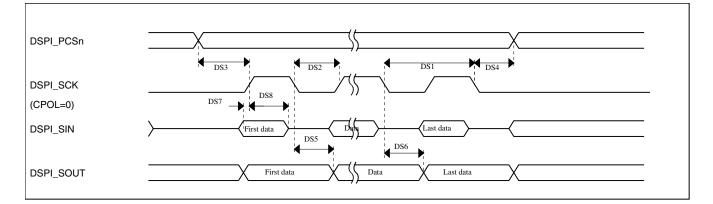




Table 43. I2S/SAI master mode timing in Normal Run, Wait and Stop modes (limited voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
S1	I2S_MCLK cycle time	40	—	ns
S2	I2S_MCLK pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	80	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	-	15	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output invalid	0	-	ns
S7	I2S_TX_BCLK to I2S_TXD valid	_	15	ns
S8	I2S_TX_BCLK to I2S_TXD invalid	0	_	ns
S9	I2S_RXD/I2S_RX_FS input setup before I2S_RX_BCLK	15	-	ns
S10	I2S_RXD/I2S_RX_FS input hold after I2S_RX_BCLK	0	—	ns

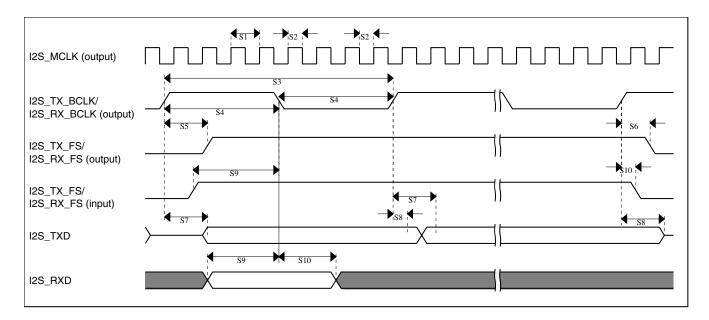


Figure 24. I2S/SAI timing — master modes

Table 44. I2S/SAI slave mode timing in Normal Run, Wait and Stop modes (limited voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
S11	I2S_TX_BCLK/I2S_RX_BCLK cycle time (input)	80	—	ns
S12	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low (input)	45%	55%	MCLK period

Table continues on the next page ...

Table 47. I2S/SAI master mode timing in VLPR, VLPW, and VLPS modes (full voltage range) (continued)

Num.	Characteristic	Min.	Max.	Unit
S1	I2S_MCLK cycle time	62.5	—	ns
S2	I2S_MCLK pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	250	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	—	45	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output invalid	0	-	ns
S7	I2S_TX_BCLK to I2S_TXD valid	—	45	ns
S8	I2S_TX_BCLK to I2S_TXD invalid	0	_	ns
S9	I2S_RXD/I2S_RX_FS input setup before I2S_RX_BCLK	45	-	ns
S10	I2S_RXD/I2S_RX_FS input hold after I2S_RX_BCLK	0	_	ns

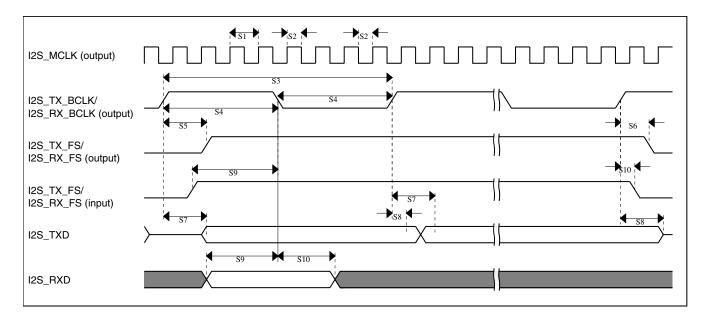


Figure 28. I2S/SAI timing — master modes

Table 48. I2S/SAI slave mode timing in VLPR, VLPW, and VLPS modes (full voltage range)

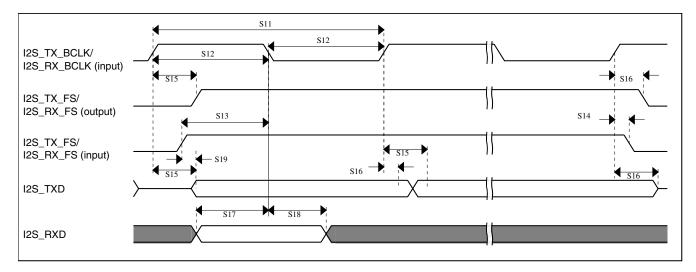
Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S11	I2S_TX_BCLK/I2S_RX_BCLK cycle time (input)	250	—	ns
S12	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low (input)	45%	55%	MCLK period

Table continues on the next page ...

Table 48. I2S/SAI slave mode timing in VLPR, VLPW, and VLPS modes (full voltage range) (continued)

Num.	Characteristic	Min.	Max.	Unit
S13	I2S_TX_FS/I2S_RX_FS input setup before I2S_TX_BCLK/I2S_RX_BCLK	30	-	ns
S14	I2S_TX_FS/I2S_RX_FS input hold after I2S_TX_BCLK/I2S_RX_BCLK	3	-	ns
S15	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output valid	-	63	ns
S16	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output invalid	0	—	ns
S17	I2S_RXD setup before I2S_RX_BCLK	30	—	ns
S18	I2S_RXD hold after I2S_RX_BCLK	2	—	ns
S19	I2S_TX_FS input assertion to I2S_TXD output valid ¹	-	72	ns

1. Applies to first bit in each frame and only if the TCR4[FSE] bit is clear





6.9 Human-machine interfaces (HMI)

6.9.1 TSI electrical specifications

Table 49. TSI electrical specifications

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
V _{DDTSI}	Operating voltage	1.71	—	3.6	V	
C _{ELE}	Target electrode capacitance range	1	20	500	pF	1
f _{REFmax}	Reference oscillator frequency	_	8	15	MHz	2, 3
f _{ELEmax}	Electrode oscillator frequency	—	1	1.8	MHz	2, 4

Table continues on the next page...

Pinout

7.1 Obtaining package dimensions

Package dimensions are provided in package drawings.

To find a package drawing, go to www.freescale.com and perform a keyword search for the drawing's document number:

If you want the drawing for this package	Then use this document number
121-pin MAPBGA	98ASA00344D

8 Pinout

8.1 K10 Signal Multiplexing and Pin Assignments

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The Port Control Module is responsible for selecting which ALT functionality is available on each pin.

121	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
MAP Bga											
E4	PTE0	ADC1_SE4a	ADC1_SE4a	PTE0	SPI1_PCS1	UART1_TX	SDHC0_D1		I2C1_SDA	RTC_CLKOUT	
E3	PTE1/ LLWU_P0	ADC1_SE5a	ADC1_SE5a	PTE1/ LLWU_P0	SPI1_SOUT	UART1_RX	SDHC0_D0		I2C1_SCL	SPI1_SIN	
E2	PTE2/ LLWU_P1	ADC1_SE6a	ADC1_SE6a	PTE2/ LLWU_P1	SPI1_SCK	UART1_CTS_b	SDHC0_DCLK				
F4	PTE3	ADC1_SE7a	ADC1_SE7a	PTE3	SPI1_SIN	UART1_RTS_b	SDHC0_CMD			SPI1_SOUT	
E7	VDD	VDD	VDD								
F7	VSS	VSS	VSS								
H7	PTE4/ LLWU_P2	DISABLED		PTE4/ LLWU_P2	SPI1_PCS0	UART3_TX	SDHC0_D3				
G4	PTE5	DISABLED		PTE5	SPI1_PCS2	UART3_RX	SDHC0_D2				
F3	PTE6	DISABLED		PTE6	SPI1_PCS3	UART3_CTS_b	I2S0_MCLK				
E6	VDD	VDD	VDD								
G7	VSS	VSS	VSS								
F1	PTE16	ADC0_SE4a	ADC0_SE4a	PTE16	SPI0_PCS0	UART2_TX	FTM_CLKIN0		FTM0_FLT3		
F2	PTE17	ADC0_SE5a	ADC0_SE5a	PTE17	SPI0_SCK	UART2_RX	FTM_CLKIN1		LPTMR0_ALT3		
G1	PTE18	ADC0_SE6a	ADC0_SE6a	PTE18	SPI0_SOUT	UART2_CTS_b	I2C0_SDA				
G2	PTE19	ADC0_SE7a	ADC0_SE7a	PTE19	SPI0_SIN	UART2_RTS_b	I2C0_SCL				
L6	VSS	VSS	VSS								
H1	ADC0_DP1	ADC0_DP1	ADC0_DP1								
H2	ADC0_DM1	ADC0_DM1	ADC0_DM1								